

Description

The μPD446 is a high-speed, low-power, 2048-word by 8-bit static CMOS RAM fabricated with advanced silicon-gate CMOS technology. A unique circuitry technique makes the μPD446 a very low operating power device which requires no clock or refreshing to operate. Minimum standby power current is drawn by this device when CS equals V_{CC} independently of the other input levels. Data retention is guaranteed at a power supply voltage as low as 2 V.

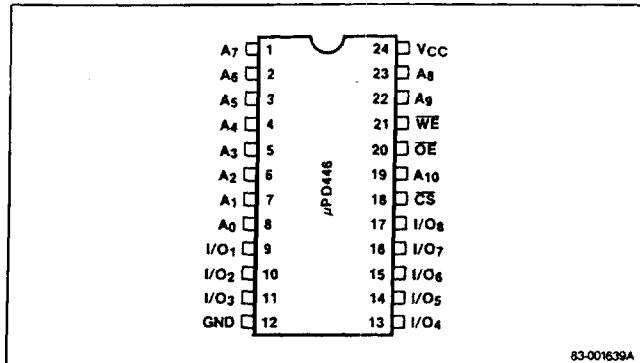
The μPD446 has a standard 24-pin dual-in-line package and is plug-in compatible with 16K EPROMs.

The μPD446 is also packaged in a miniflat package providing high density application.

Features

- Single +5 V supply
- Fully static operation — no clock or refreshing required
- TTL compatible — all inputs and outputs
- Common I/O using three-state output
- OE eliminates need for external bus buffers
- Max access/min cycle times down to 150 ns
- Low power dissipation
 - Active: 38 mA max
 - Standby: 10 μA max
- Data retention voltage: 2 V min
- Operating temperature range: -40°C to +85°C
- Standard 24-pin plastic package (μPD446C)
- Plug-in compatible with 16K EPROMs (μPD446C)
- Miniflat package for high density application (μPD446G)
- L version
 - Standby current 1.0 μA max at 60°C for battery backup operation

Pin Configuration



83-001639A

Pin Identification

No.	Symbol	Function
1-8, 19, 22, 23	A ₀ -A ₁₀	Address input
9-11, 13-17	I/O ₁ -I/O ₈	Data input / output
18	CS	Chip select
20	OE	Output enable
21	WE	Write enable
24	V _{CC}	Power (+5 V)
12	GND	GND

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Performance Ranges

Device	Access Time (Max)	Cycle Time (Min)	Power Supply (Max)	
			Active	Standby
μPD446C-3, 446G-15	150 ns	150 ns	38 mA	(Note 1)
μPD446C-2, 446G-20	200 ns	200 ns	30 mA	(Note 1)
μPD446C-1, 446G-25	250 ns	250 ns	26 mA	(Note 1)
μPD446C, 446G-45	450 ns	450 ns	18 mA	(Note 1)

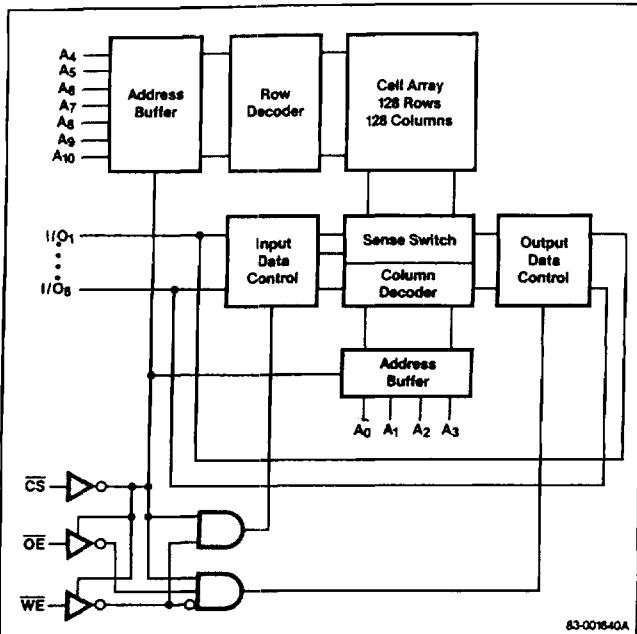
Note:

(1) μPD446C-L/-1L/-2L/-3L, μPD446G-45L/25L/20L/15L

T_A = 25°C, 0.2 μA
T_A = 60°C, 1.0 μA
T_A = 85°C, 10 μA

μPD446C/-1/-2/-3, μPD446G-45/25/20/15

T_A = 25°C, 1.0 μA
T_A = 60°C, 5.0 μA
T_A = 85°C, 10 μA

Block Diagram**Absolute Maximum Ratings**

Power supply voltage, V_{CC}	7.0 V
Input voltage, V_{IN}	-0.3 to $V_{CC} + 0.3$ V
Output voltage, V_{OUT}	-0.3 to $V_{CC} + 0.3$ V
Operating temperature, T_{OPR}	-40 to 85°C
Storage temperature, T_{STG}	-55 to 125°C

Comment: Exposing the device to stresses above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational sections of the specification. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Capacitance $T_A = 25^\circ\text{C}$, $f = 1\text{MHz}$

Parameter	Symbol	Limits				Test Conditions
		Min	Typ	Max	Unit	
Input capacitance	C_{IN}		6	pF		$V_{IN} = 0\text{V}$
Input/output capacitance	$C_{I/O}$		8	pF		$V_{I/O} = 0\text{V}$

Recommended DC Operating Conditions $T_A = -40 \text{ to } +85^\circ\text{C}$

Parameter	Symbol	Limits			
		Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
Input voltage low	V_{IL}	-0.3		0.8	V
Input voltage high	V_{IH}	2.2		$V_{CC} + 0.3$	V

DC Characteristics $T_A = -40 \text{ to } 85^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$

Parameter	Symbol	Limits				Test Conditions
		Min	Typ	Max	Unit	
Input leakage current	I_{LI}		1	μA	$V_{IN} = 0\text{V}$ to V_{CC}	
I/O leakage current	I_{LO}		1	μA	$V_{I/O} = 0\text{V}$ to V_{CC} $\overline{CS} = V_{IH}$ or $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$	
Operating supply current	I_{CCA1}	(1)	(1)	mA	$\overline{CS} = V_{IL}$, $I_{I/O} = 0\text{V}$ min cycle	
Operating supply current	I_{CCA2}	5	10	mA	$\overline{CS} = V_{IL}$, $I_{I/O} = 0\text{V DC}$ current	
Standby supply current	I_{CCS}	0.02	(2)	μA	$\overline{CS} = V_{CC} - 0.2\text{V}$, $V_{IN} = 0\text{V}$ to V_{CC}	
Output voltage low	V_{OL}		0.4	V	$I_{OL} = 2.0\text{ mA}$	
Output voltage high	V_{OH}	2.4		V	$I_{OH} = -1.0\text{ mA}$	

Notes:(1) $\mu\text{PD446C-3/3L}$, $\mu\text{PD446G-15/15L}$: 25 mA typ, 38 mA max $\mu\text{PD446C-2/2L}$, $\mu\text{PD446G-20/20L}$: 20 mA typ, 30 mA max $\mu\text{PD446C-1/1L}$, $\mu\text{PD446G-25/25L}$: 18 mA typ, 26 mA max $\mu\text{PD446C/-L}$, $\mu\text{PD446G-45/45L}$: 12 mA typ, 18 mA max(2) $\mu\text{PD446C-L/-1L/-2L/-3L}$, $\mu\text{PD446G-45/25L/20L/15L}$ $T_A = 25^\circ\text{C}$, 0.2 μA $T_A = 60^\circ\text{C}$, 1.0 μA $T_A = 85^\circ\text{C}$, 10 μA $\mu\text{PD446C/-1/-2/-3}$, $\mu\text{PD446G-45/25/20/15}$ $T_A = 25^\circ\text{C}$, 1.0 μA $T_A = 60^\circ\text{C}$, 5.0 μA $T_A = 85^\circ\text{C}$, 10 μA

AC Characteristics $T_A = -40 \text{ to } 85^\circ\text{C}, V_{CC} = 5 \text{ V} \pm 10\%$

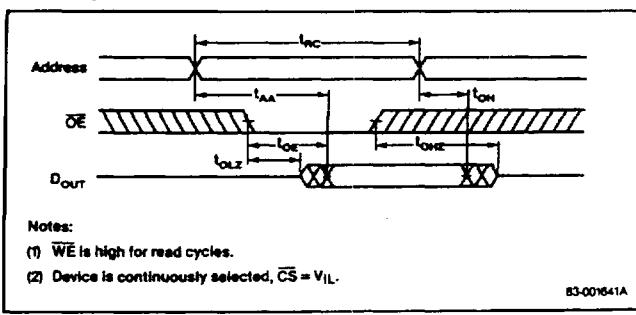
Parameter	Symbol	μ PD446C-3 μ PD446G-15	μ PD446C-2 μ PD446G-20	μ PD446C-1 μ PD446G-25	μ PD446C μ PD446G-45	Min	Max	Min	Max	Min	Max	Unit
Read Cycle												
Read cycle time	t_{RC}	150	200	250	450							ns
Address access time	t_{AA}		150	200	250							ns
Chip select access time	t_{ACS}	150	200	250	450							ns
Output enable to output valid	t_{OE}	75	100	120	150							ns
Output hold from address change	t_{OH}	15	15	15	15							ns
Chip select to output in Lo-Z	t_{CLZ}	10	10	10	10							ns
Output enable to output in Lo-Z	t_{OLZ}	5	5	5	5							ns
Chip deselect to output in Hi-Z	t_{CHZ}		50	60	80							ns
Output disable to output in Hi-Z	t_{OHZ}		50	60	80							ns
Write Cycle												
Write cycle time	t_{WC}	150	200	250	450							ns
Chip select to end of write	t_{CW}	120	150	180	210							ns
Address valid to end of write	t_{AW}	120	150	180	210							ns
Address setup time	t_{AS}	0	0	0	0							ns
Write pulse width	t_{WP}	90	120	150	180							ns
Write recovery time	t_{WR}	0	0	0	0							ns
Data valid to end of write	t_{DW}	50	60	80	100							ns
Data hold time	t_{DH}	0	0	0	0							ns
Write enable to output in Hi-Z	t_{WHZ}		50	60	80							ns
Output active from end of write	t_{OW}	10	10	10	10							ns

AC Test Conditions

Input pulse levels	0.8 to 2.2 V
Input pulse rise and fall time	10 ns
Timing reference levels	1.5 V
Output load	1 TTL + 100 pF

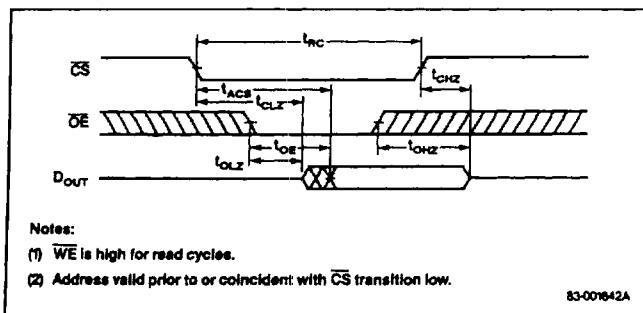
Truth Table

CS	OE	WE	MODE	I/O	I_{cc}
H	X	X	Not selected	Hi-Z	Standby
L	H	H	Not selected	Hi-Z	Active
L	L	H	Read	D _{OUT}	Active
L	X	L	Write	D _{IN}	Active

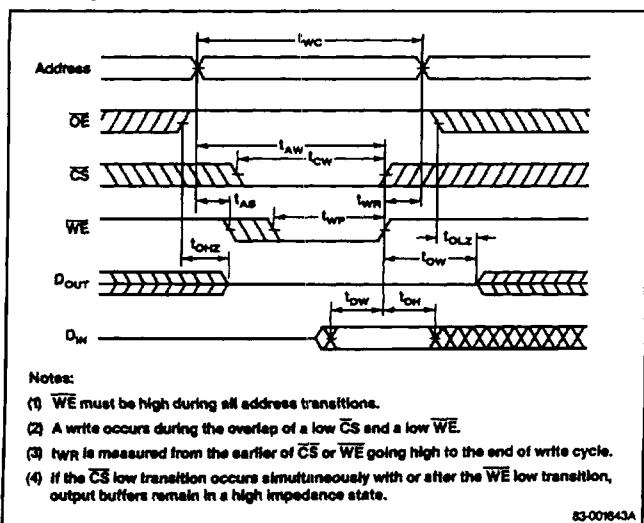
Timing Waveforms**Read Cycle No. 1**

Timing Waveforms (cont)

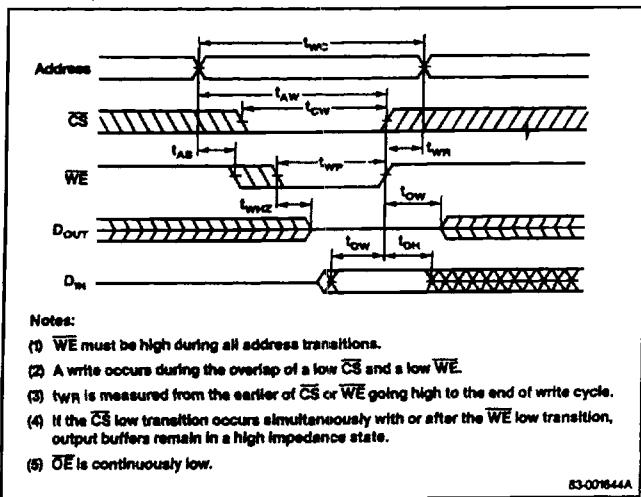
Read Cycle No. 2



Write Cycle No. 1



Write Cycle No. 2



Low V_{CC} Data Retention Characteristics

T_A = -40 to 85°C

Parameter	Symbol	Limits			Test Conditions
		Min	Typ	Max	
Data retention supply voltage	V _{CCDR}	2.0			V _{IN} = 0 V to V _{CC} , CS = V _{CC}
Data retention supply current	I _{CCDR}		0.01 (1)		μ A V _{IN} = 0 V to V _{CC} , CS = V _{CC} , V _{CC} = 3.0 V
Chip deselection	t _{CDR}	0			ns
to data retention mode					
Operation recovery time	t _R		t _{RC}		ns

Note:

(1) μ PD446C-L/-1L/-2L/-3L, μ PD446G-45L/25L/20L/15L

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μ PD446C/-1/-2/-3, μ PD446G-45/25/20/15

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Low V_{CC} Data Retention

